

<b>Notice of References Cited</b>	Application/Control No. 10/663,976	Applicant(s)/Patent Under Reexamination MIRKIN ET AL.	
	Examiner Alain L. Bashore	Art Unit 1762	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,573,369 B2	06-2003	Henderson et al.	536/23.1
*	C	US-5,246,609 A	09-1993	Nakata et al.	252/62.59
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Jaschke et al; Deposition of Organic Material by the tip of a scanning Force Microscope; Langmuir; 1995; 11; 1061-1064.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.